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Application/Control No.	Applicant(s)/Patent under Reexamination
10/608,721	ASHMORE ET AL.
Examiner.	Art Unit
Hetul Patel	2186

SEARCHED				
Subclass	Date	Examiner		
				
•				
	Subclass	Subclass Date		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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	1			

SEARCH NOT (INCLUDING SEARCH S)
	DATE	EXMR
Consulted w/ Todd Swann for finding out whether it will be considered new matter by adding "the non-testing mode" phrase in	·	
claim 1 and other independent claims? Todd suggested it will not be a new matter issue since spec is silent about specifying		
testing or non-testing mode (means both are supported)	3/22/2006	НВР
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